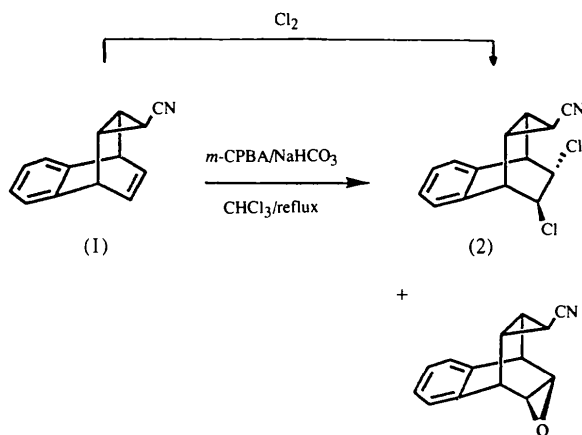


Lists of structure factors, anisotropic displacement parameters, H-atom coordinates and complete geometry have been deposited with the IUCr (Reference: AS1193). Copies may be obtained through The Managing Editor, International Union of Crystallography, 5 Abbey Square, Chester CH1 2HU, England.

References

- Enraf-Nonius (1989). *CAD-4 Software*. Version 5.0. Enraf-Nonius, Delft, The Netherlands.
- Fan, H. F. (1991). *SAPI91. Structure Analysis Programs with Intelligent Control*. Rigaku Corporation, Tokyo, Japan.
- Johnson, C. K. (1976). *ORTEPII*. Report ORNL-5138. Oak Ridge National Laboratory, Tennessee, USA.
- Molecular Structure Corporation (1992). *TEXSAN. Crystal Structure Analysis Package*. MSC, 3200, Research Forest Drive, The Woodlands, TX 77381, USA.
- Ueno, K. (1985). *Acta Cryst.* **C41**, 1786–1789.

tetrahydro-2,7-etheno-1*H*-cyclopropa[*b*]naphthalene-1-carbonitrile, (1), in CHCl₃ was reacted with *m*-chloroperbenzoic acid (*m*-CPBA) in order to find out whether electrophiles can attack the double bond from the *endo* face or the *exo* face. Compound (2) was obtained as the major product.



Acta Cryst. (1995). **C51**, 2714–2715

Unusual Chlorination During an Epoxidation Reaction of an Etheno-cyclopropa[*b*]naphthalene Derivative

DIÑÇER ÜLKÜ AND M. NAWAZ TAHIR

Department of Engineering Physics, Hacettepe University, 06532 Beytepe, Ankara, Turkey

ABDULLAH MENZEK AND METİN BALCI

Department of Chemistry, Atatürk University, 24240 Erzurum, Turkey

(Received 1 May 1995; accepted 10 July 1995)

Abstract

The structure of (1 α ,1 α ,2 β ,7 α ,8*R*,9*R*)-8,9-dichloro-1 α ,2,7,7 α -tetrahydro-2,7-ethano-1*H*-cyclopropa[*b*]naphthalene-1-carbonitrile, C₁₄H₁₁Cl₂N, consists of two non-planar six-membered carbon rings (constituting a [2.2.2] bicyclic system), one of which shares two C atoms with a benzene ring and has two Cl substituents; the other is fused to a cyclopropane ring carrying a C≡N substituent. The two Cl atoms of the —C—C(Cl)—C(Cl)—C— bridging system have an *anti* arrangement with respect to the plane of the four C atoms.

Comment

In connection with our recently developed high-temperature bromination reactions (Dastan & Balcı, 1994; Dastan, Balcı, Hókelek, Ülkü & Büyükgüngör, 1994), a solution of the *exo*-cyano compound 1 α ,2,7,7 α -

During this reaction we expected only the formation of an epoxide. The formation of a chlorinated compound is unusual. We believe that *m*-chloroperbenzoic acid (as an oxidative reagent) forms chlorine upon oxidation of the chloroform used as solvent, which adds to the double bond. The mechanism of formation of this product is currently under investigation. The same compound was also synthesized by an independent route involving direct chlorination (yield 55%).

The least-squares plane through C1, C2, C3, C4, C5, C6, C11 and C12 indicates that C11 and C12 lie practically in the plane of the benzene ring (Fig. 1), being displaced by 0.032 (7) and –0.008 (8) Å, respectively, from the plane of the benzene ring. The C11—C13 [1.799 (9) Å] and C12—C14 [1.795 (8) Å] bond lengths are not significantly different. The C11—C13—

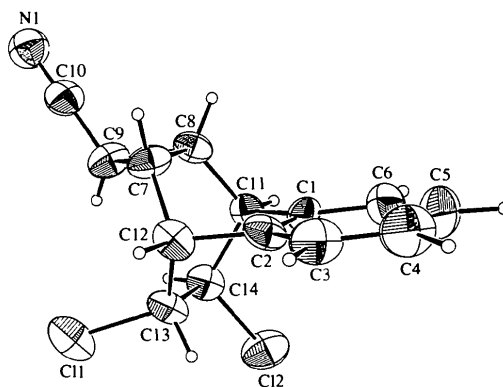


Fig. 1. ORTEPII (Johnson, 1976) drawing of C₁₄H₁₁Cl₂N with the atom-numbering scheme. The displacement ellipsoids are drawn at the 50% probability level.

C14 and C12—C14—C13 bond angles are 110.7 (6) and 109.7 (5)°, respectively. This results in a symmetrical *anti* arrangement of the Cl atoms with respect to the plane of C11, C12, C13 and C14.

Experimental

To a solution of the *exo*-cyano compound (1) in CHCl₃, NaHCO₃ and *m*-chloroperbenzoic acid (*m*-CPBA) were added. The resulting mixture was refluxed for 4 h and the resulting precipitate removed by filtration. Colourless crystals of the dichloro compound (2) were isolated. (See *Comment.*)

Crystal data

C₁₄H₁₁Cl₂N
M_r = 264.156
 Monoclinic
*C*2/*c*
a = 30.403 (1) Å
b = 8.130 (1) Å
c = 10.354 (2) Å
 β = 101.889 (1)°
V = 2504.2 (7) Å³
Z = 8
D_x = 1.401 Mg m⁻³

Mo *K*α radiation
 λ = 0.71073 Å
 Cell parameters from 16 reflections
 θ = 8.25–18.17°
 μ = 0.47 mm⁻¹
T = 295 K
 Plate
 0.35 × 0.25 × 0.15 mm
 Colourless

Data collection

Enraf–Nonius CAD-4 diffractometer
 ω/2θ scans
 Absorption correction: ψ scan (*MolEN*; Fair, 1990)
T_{min} = 0.85, *T_{max}* = 0.99
 1805 measured reflections
 1577 independent reflections
 753 observed reflections
 [*I* ≥ 2σ(*I*)]

R_{int} = 0.029
 θ_{max} = 22.79°
h = -32 → 32
k = -8 → 0
l = 0 → 11
 3 standard reflections
 frequency: 120 min
 intensity decay: 2.14% (corrected)

Refinement

Refinement on *F*
R = 0.056
wR = 0.050
S = 1.35
 691 reflections
 187 parameters
 Only coordinates of H atoms refined
w = 1/σ²(*F*)

(Δ/σ)_{max} = 0.0004
 Δρ_{max} = 0.164 e Å⁻³
 Δρ_{min} = -0.163 e Å⁻³
 Extinction correction: none
 Atomic scattering factors from *International Tables for X-ray Crystallography* (1974, Vol. IV)

Table 1. Fractional atomic coordinates and equivalent isotropic displacement parameters (Å²)

	$B_{eq} = (4/3)\sum_i \sum_j \beta_{ij} a_i \cdot a_j$			
	<i>x</i>	<i>y</i>	<i>z</i>	<i>B_{eq}</i>
C11	0.92496 (9)	0.2206 (3)	0.6539 (2)	5.15 (6)
C12	0.81779 (8)	0.0526 (3)	0.7528 (3)	4.94 (6)
N1	1.0378 (2)	0.1942 (9)	1.1310 (7)	4.5 (2)
C1	0.8433 (2)	0.3357 (9)	0.9674 (7)	2.8 (2)
C2	0.8590 (3)	0.4634 (10)	0.8973 (8)	3.3 (2)
C3	0.8353 (3)	0.6109 (11)	0.8839 (9)	4.4 (3)
C4	0.7980 (3)	0.6297 (12)	0.9373 (9)	5.1 (3)

C5	0.7834 (3)	0.5031 (12)	1.0040 (12)	5.4 (3)
C6	0.8059 (3)	0.3559 (12)	1.0196 (8)	4.1 (2)
C7	0.9354 (3)	0.3738 (10)	0.9659 (8)	3.1 (2)
C8	0.9197 (3)	0.2345 (9)	1.0387 (7)	2.9 (2)
C9	0.9599 (3)	0.2116 (10)	0.9753 (8)	3.5 (2)
C10	1.0031 (3)	0.2002 (10)	1.0626 (8)	3.5 (2)
C11	0.8723 (2)	0.1816 (10)	0.9698 (7)	2.9 (2)
C12	0.9007 (3)	0.4204 (10)	0.8468 (7)	3.0 (2)
C13	0.8849 (3)	0.2780 (10)	0.7517 (7)	3.4 (2)
C14	0.8725 (3)	0.1275 (10)	0.8298 (8)	3.2 (2)

Table 2. Selected geometric parameters (Å, °)

C11—C13	1.799 (9)	C5—C6	1.37 (1)
C12—C14	1.795 (8)	C7—C8	1.49 (1)
N1—C10	1.14 (1)	C7—C9	1.51 (1)
C1—C2	1.41 (1)	C7—C12	1.50 (1)
C1—C6	1.37 (1)	C8—C9	1.51 (1)
C1—C11	1.53 (1)	C8—C11	1.53 (1)
C2—C3	1.39 (1)	C9—C10	1.44 (1)
C2—C12	1.51 (1)	C11—C14	1.52 (1)
C3—C4	1.37 (1)	C12—C13	1.53 (1)
C4—C5	1.36 (1)	C13—C14	1.56 (1)
C2—C1—C6	120.9 (8)	C7—C9—C8	59.2 (5)
C2—C1—C11	111.0 (7)	C7—C9—C10	118.2 (7)
C6—C1—C11	128.0 (8)	C8—C9—C10	116.8 (7)
C1—C2—C3	117.7 (8)	N1—C10—C9	178.5 (9)
C1—C2—C12	113.9 (7)	C1—C11—C8	105.2 (6)
C3—C2—C12	128.4 (8)	C1—C11—C14	109.8 (6)
C2—C3—C4	120.8 (9)	C8—C11—C14	109.7 (6)
C3—C4—C5	120.2 (9)	C2—C12—C7	105.8 (6)
C4—C5—C6	120.8 (9)	C2—C12—C13	102.8 (6)
C1—C6—C5	119.6 (9)	C7—C12—C13	114.5 (7)
C8—C7—C9	60.6 (6)	C11—C13—C12	113.4 (6)
C8—C7—C12	111.3 (6)	C11—C13—C14	110.7 (6)
C9—C7—C12	121.9 (7)	C12—C13—C14	109.8 (6)
C7—C8—C9	60.2 (6)	C12—C14—C11	109.7 (6)
C7—C8—C11	110.2 (6)	C12—C14—C13	109.7 (5)
C9—C8—C11	122.0 (6)	C11—C14—C13	108.5 (7)
C11—C13—C14—C12	-104.2 (5)	C11—C13—C14—C11	135.9 (6)
C11—C13—C12—C7	-75.4 (8)	C11—C13—C12—C2	170.3 (5)
C12—C14—C13—C12	129.9 (6)	C12—C14—C11—C1	-68.8 (7)
C12—C14—C11—C8	176.1 (6)		

Data collection: *CAD-4 Express* (Enraf–Nonius, 1993). Cell refinement: *CAD-4 Express*. Data reduction: *MolEN* (Fair, 1990). Program(s) used to solve structure: *MolEN SIR*. Program(s) used to refine structure: *MolEN LSFM*. Molecular graphics: *ORTEPII* (Johnson, 1976). Software used to prepare material for publication: *MolEN*.

The authors wish to acknowledge the purchase of a CAD-4 diffractometer under grant DPT/TBAG1 of the Scientific and Technical Research Council of Turkey.

Lists of structure factors, anisotropic displacement parameters, H-atom coordinates and complete geometry have been deposited with the IUCr (Reference: NA1187). Copies may be obtained through The Managing Editor, International Union of Crystallography, 5 Abbey Square, Chester CH1 2HU, England.

References

Dastan, A. & Balci, M. (1994). *J. Org. Chem.* **59**, 6534–6538.
 Dastan, A., Balci, M., Hókelek, T., Ülkü, D. & Büyükgüngör, O. (1994). *Tetrahedron*, **50**, 10555–10578.
 Enraf–Nonius (1993). *CAD-4 Express*. Version 1.1. Enraf–Nonius, Delft, The Netherlands.
 Fair, C. K. (1990). *MolEN. An Interactive Intelligent System for Crystal Structure Analysis*. Enraf–Nonius, Delft, The Netherlands.
 Johnson, C. K. (1976). *ORTEPII*. Report ORNL-5138. Oak Ridge National Laboratory, Tennessee, USA.